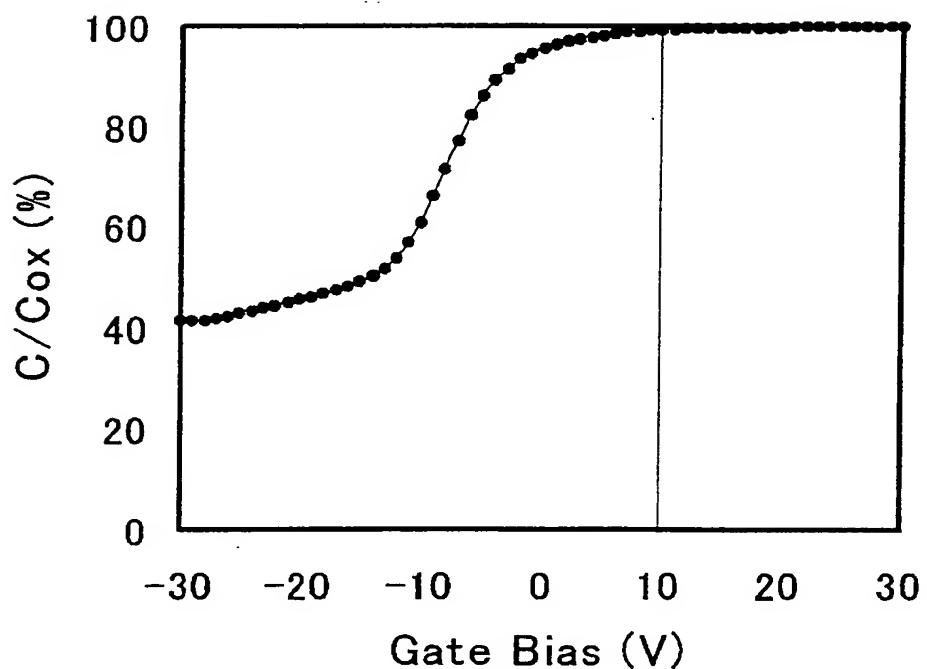
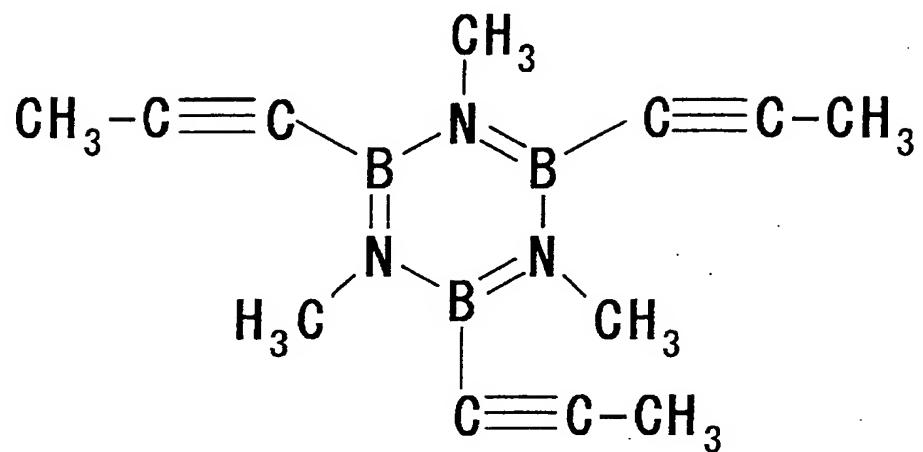




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REPLACEMENT DRAWINGS

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F I G. 1a



F I G. 1b

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FIG. 2a

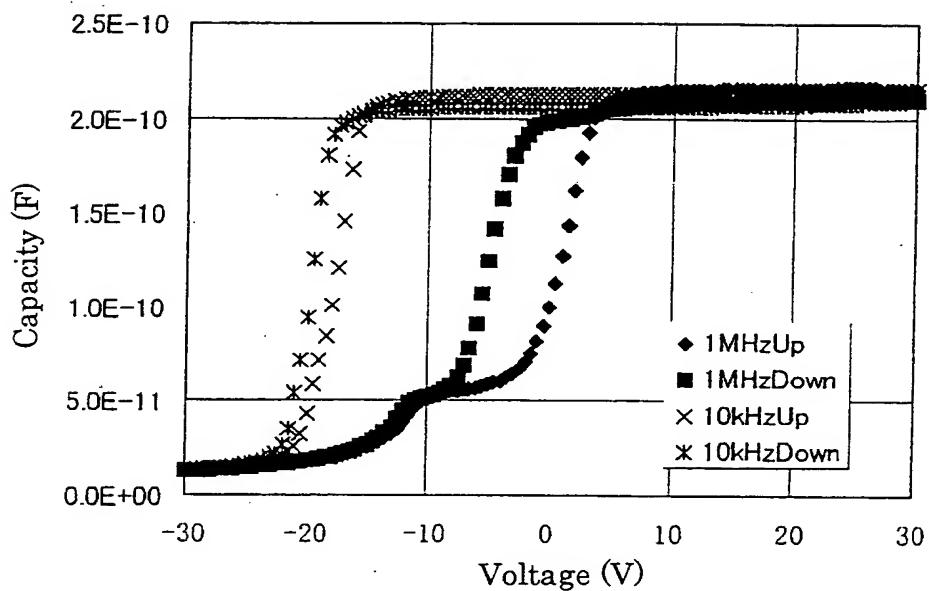
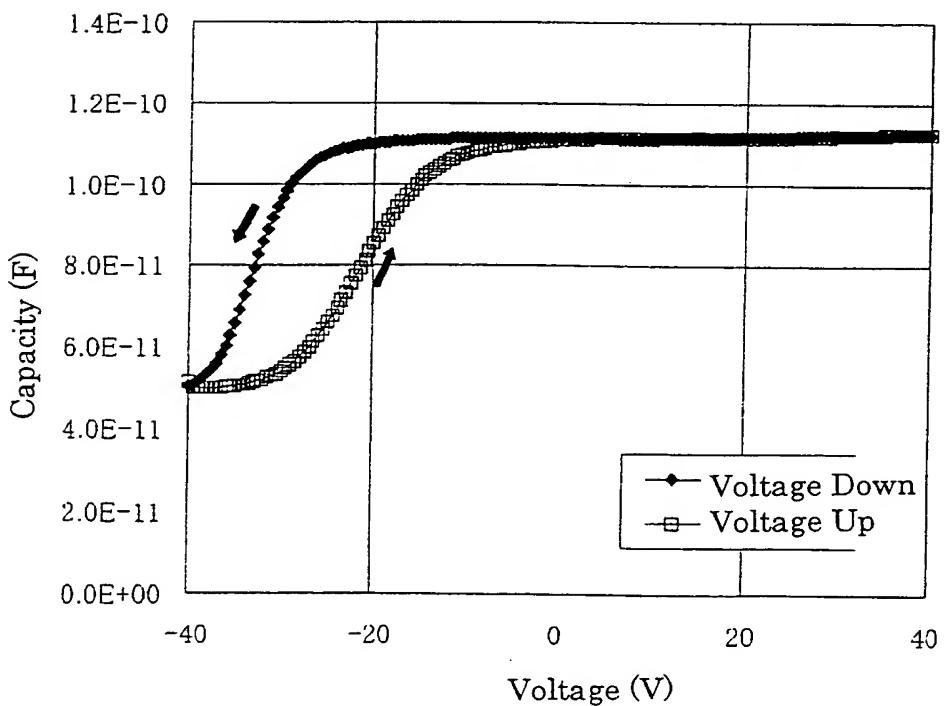


FIG. 2b



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FIG. 3a

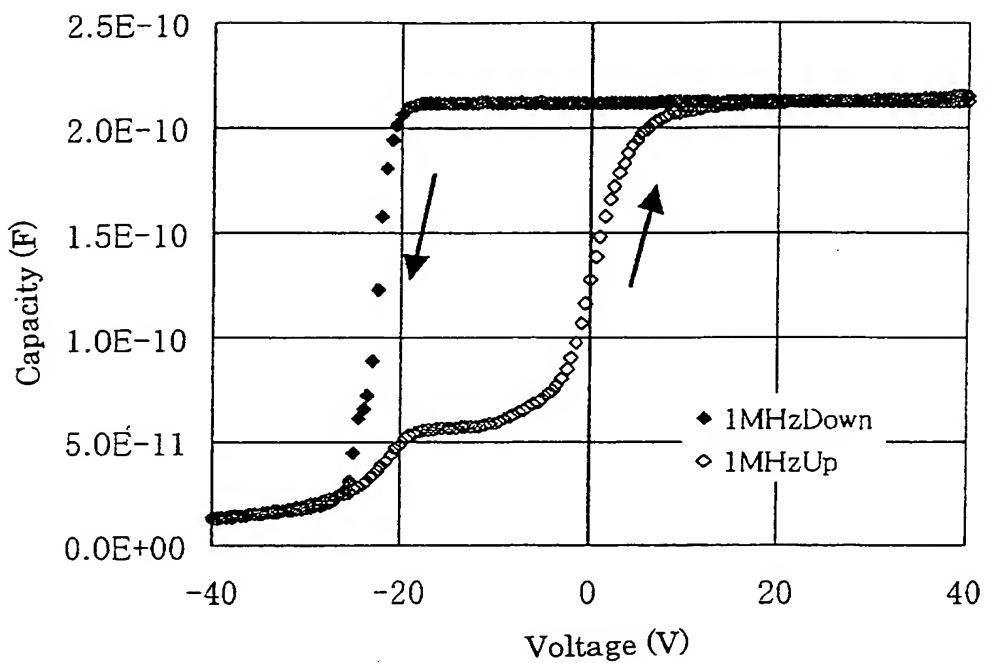


FIG. 3b

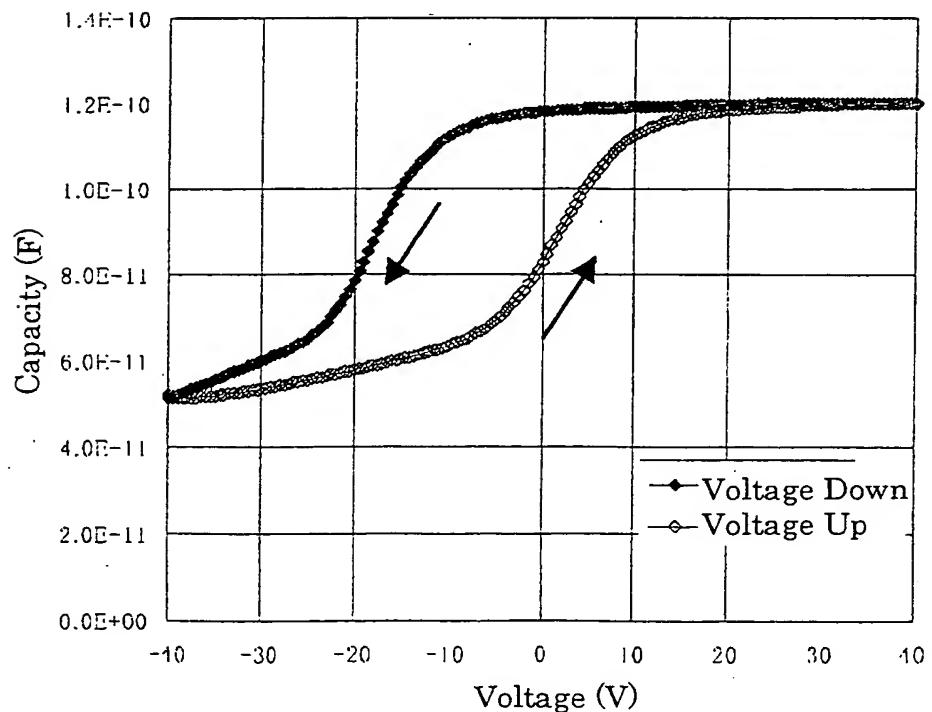
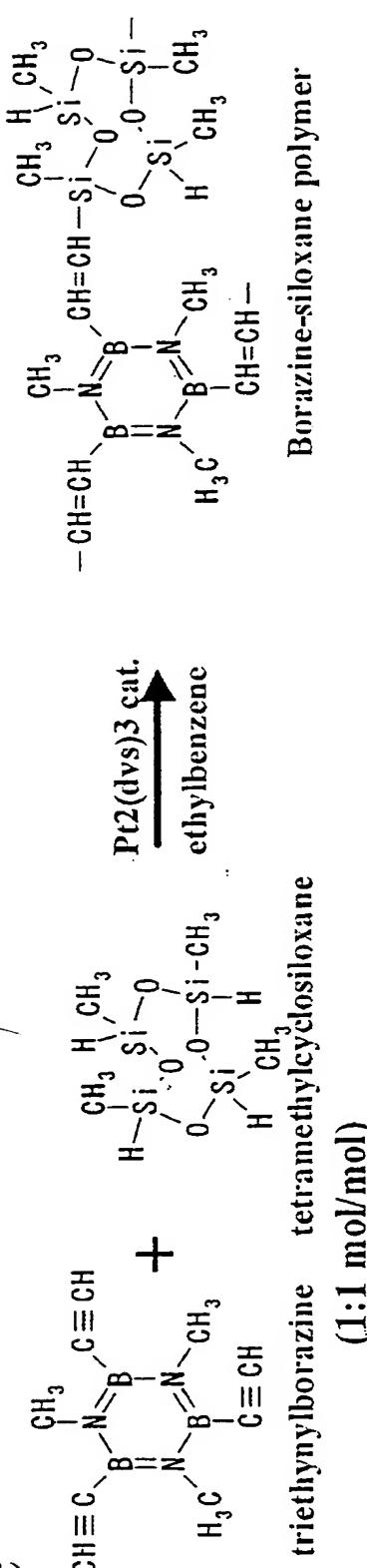
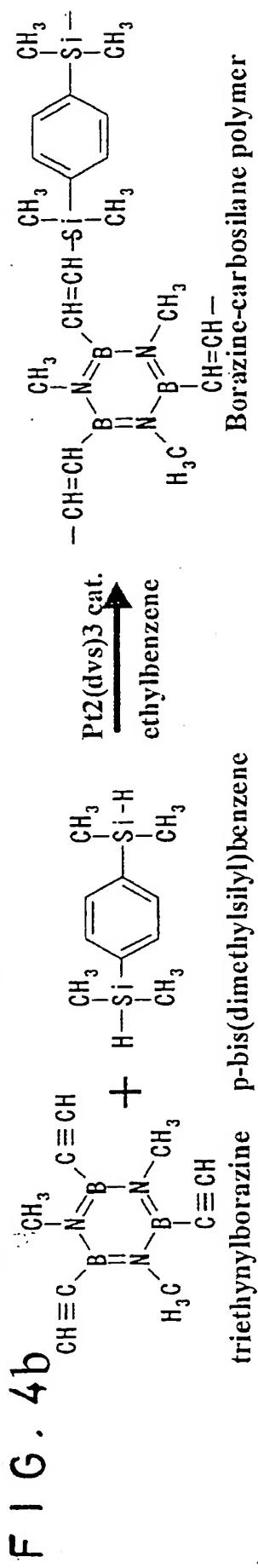
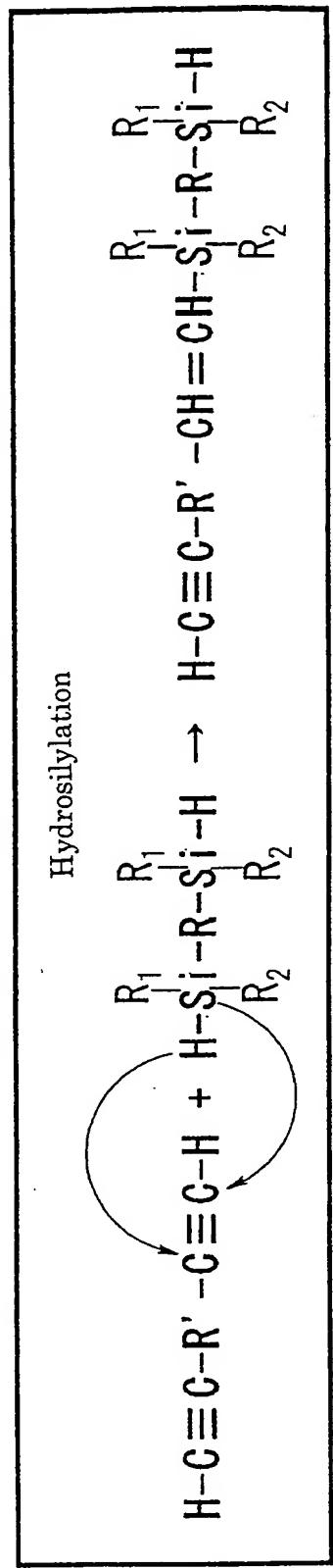
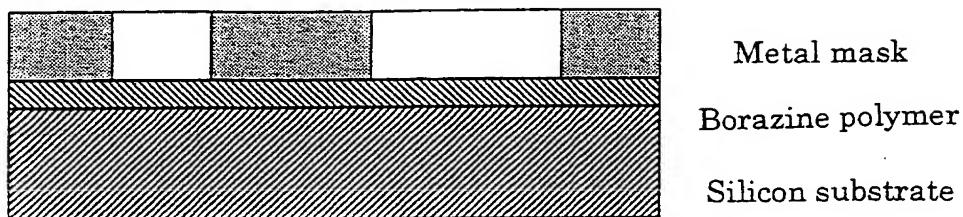


FIG. 4a

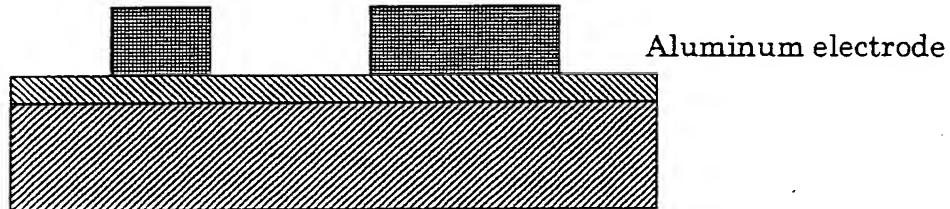


Attachment of metal mask to sample

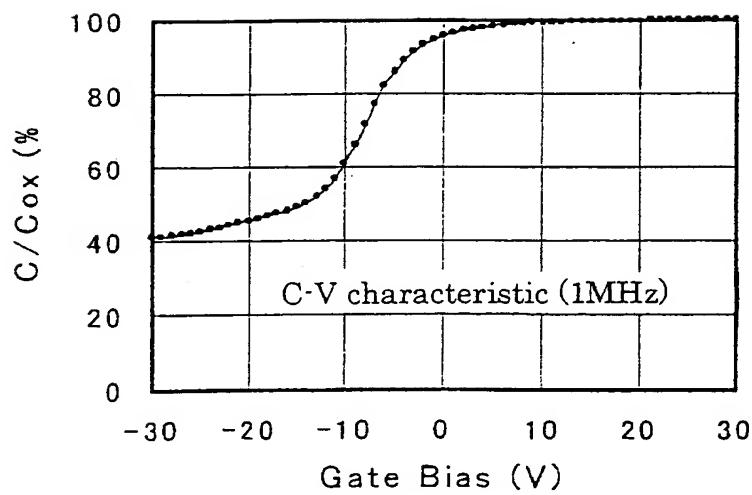


F I G. 5a

Removal of mask after evaporation of aluminum



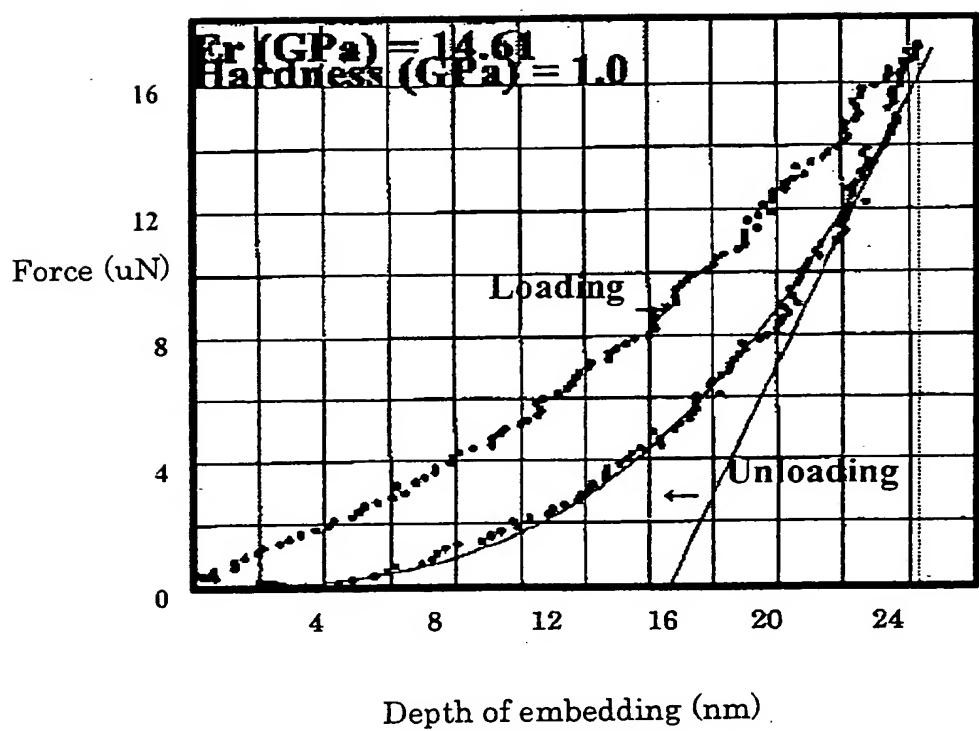
F I G. 5b



F I G. 5c

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F I G. 6



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FIG. 7a

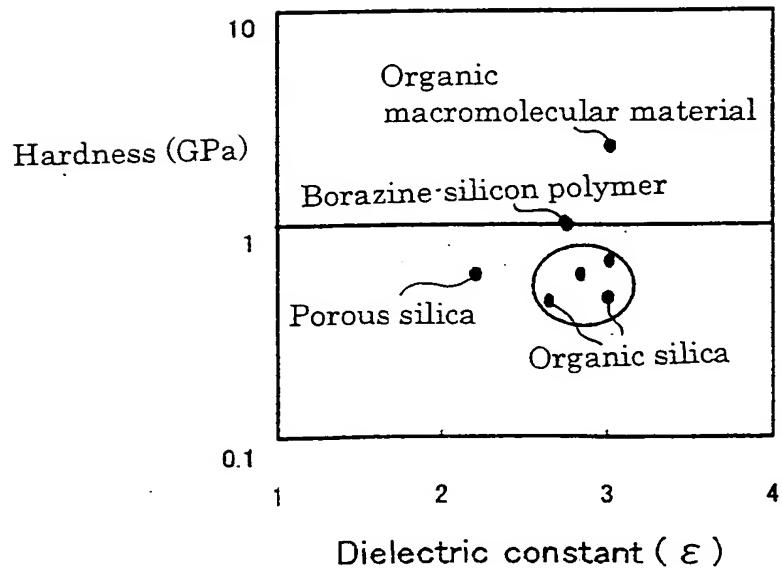
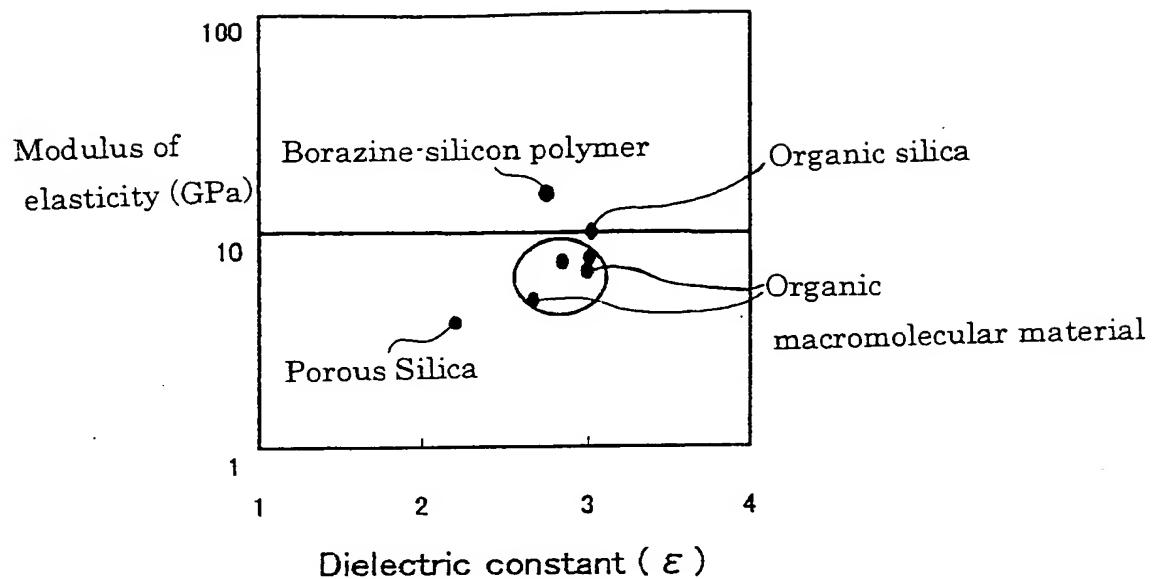
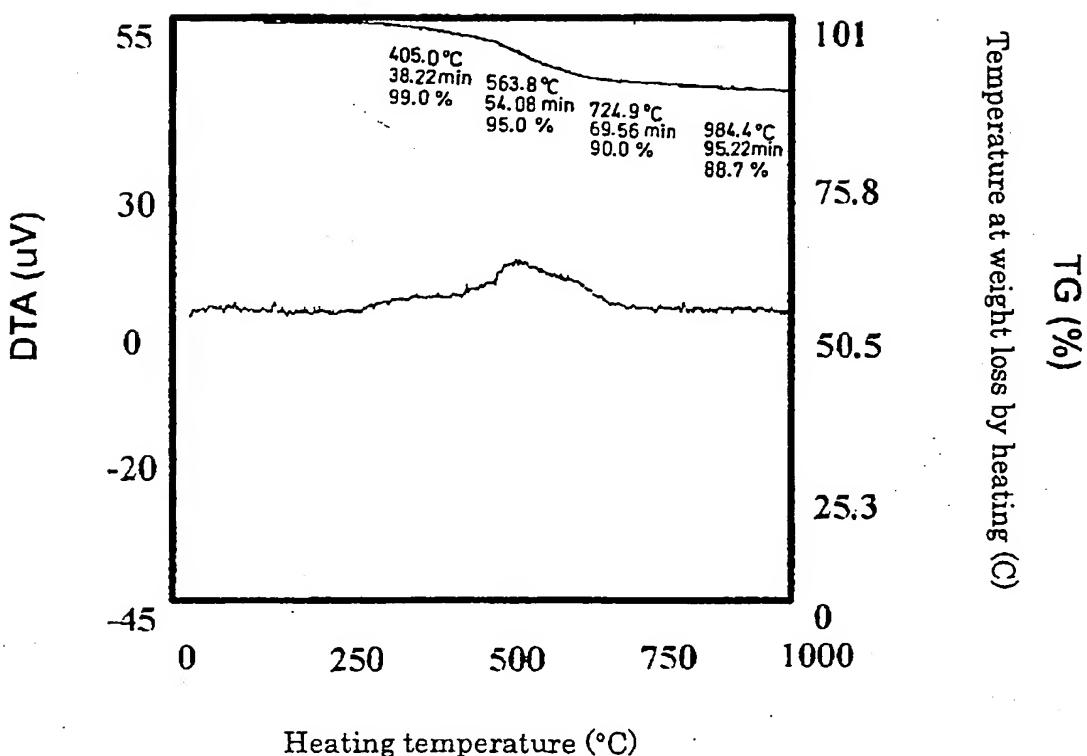


FIG. 7b

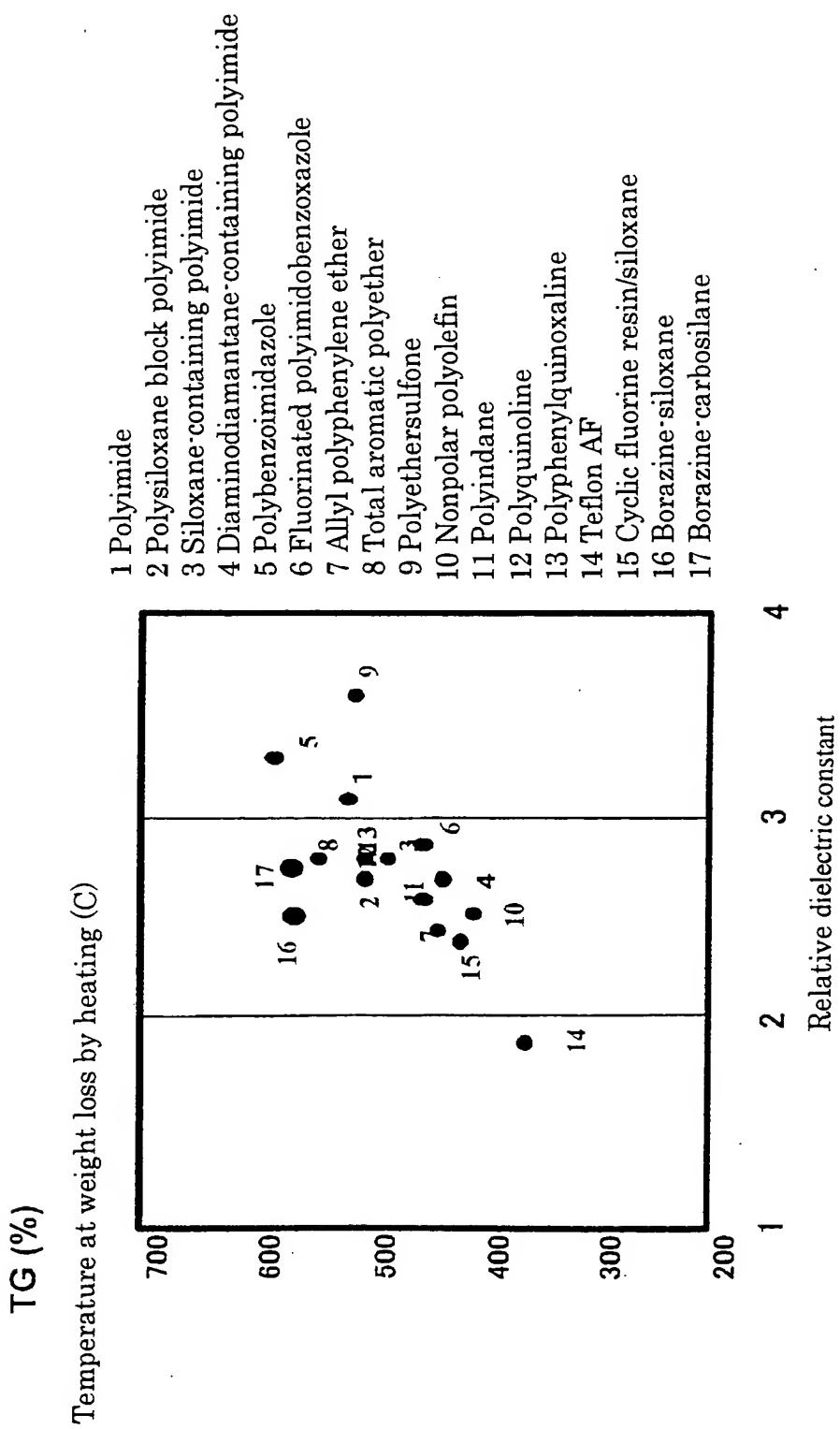
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FIG. 8



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F - G . 9



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FIG. 10

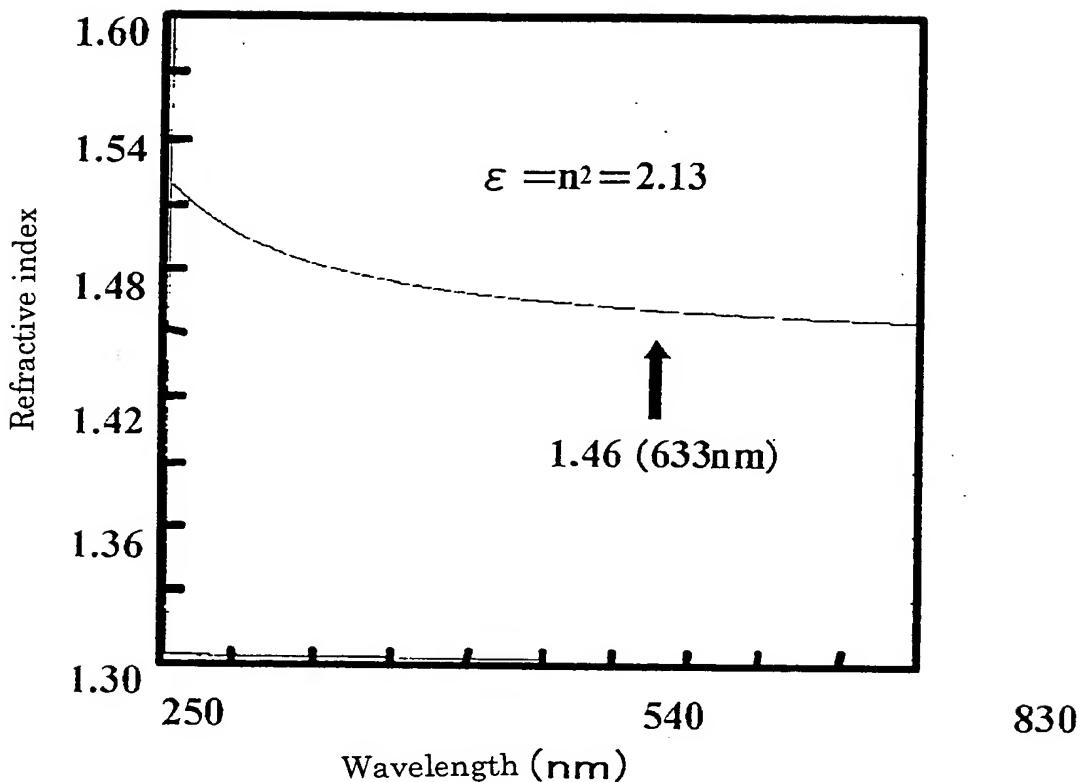
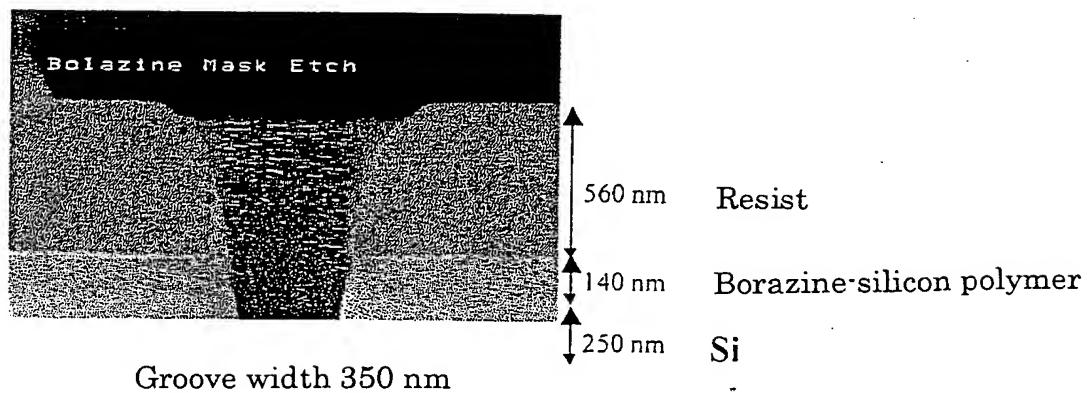


FIG. 11



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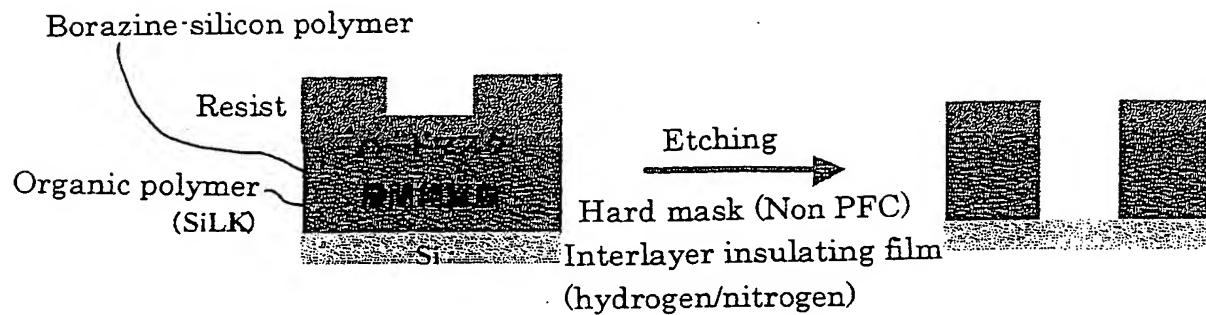


FIG. 12a

FIG. 12b

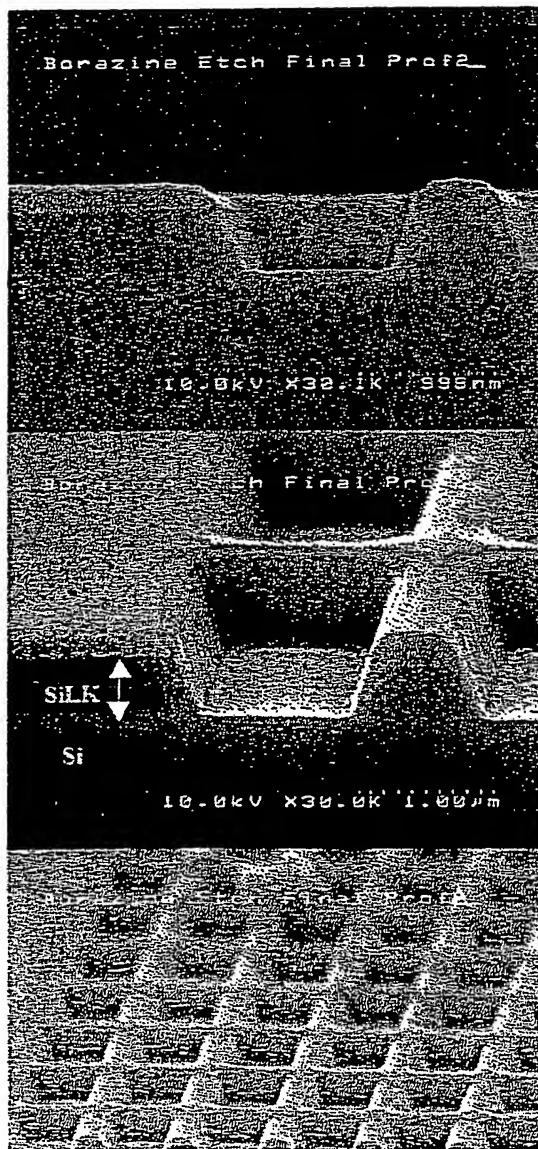


FIG. 12c

FIG. 12d

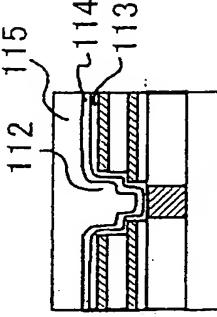
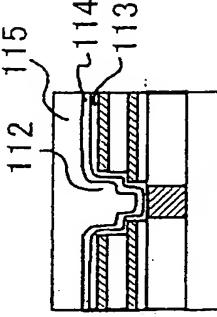
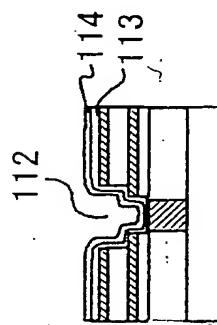
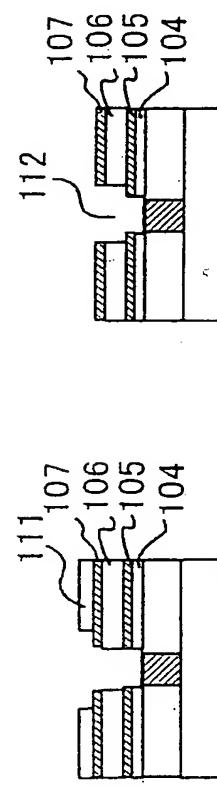
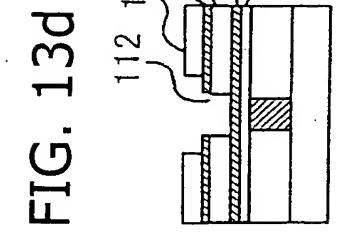
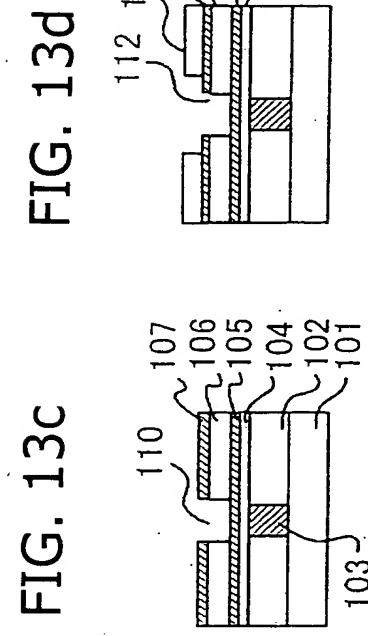
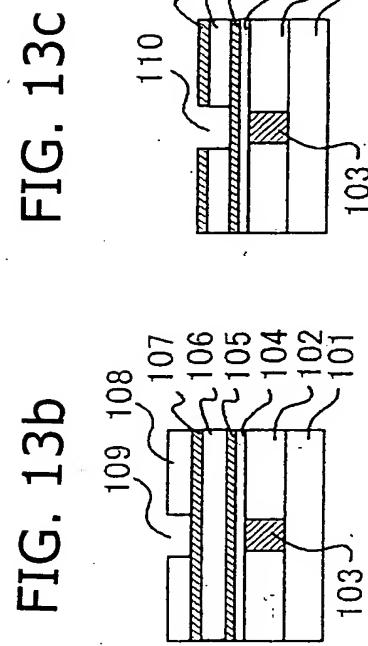
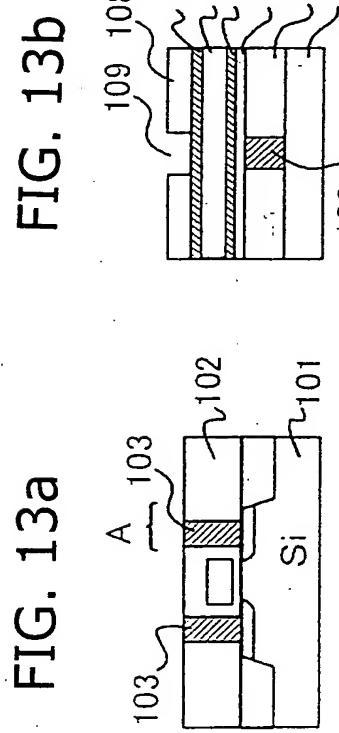


FIG. 13i

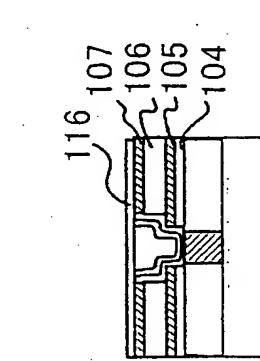


FIG. 13j

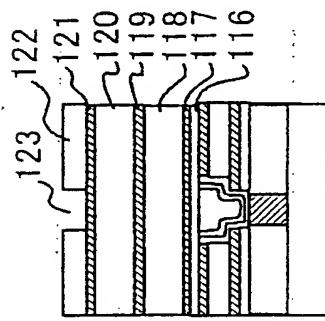


FIG. 13k

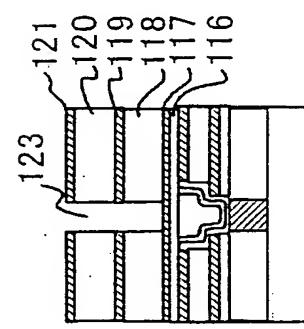


FIG. 13l

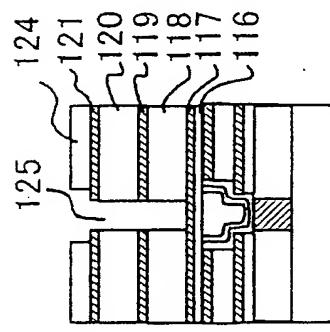


FIG. 13m

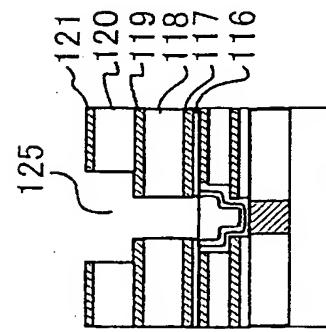


FIG. 13n

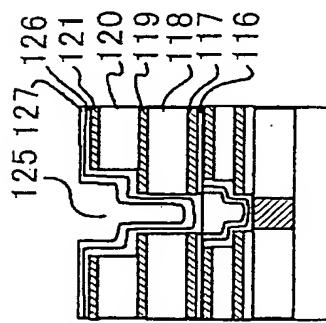


FIG. 13o

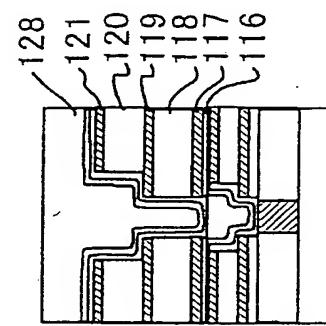


FIG. 13p

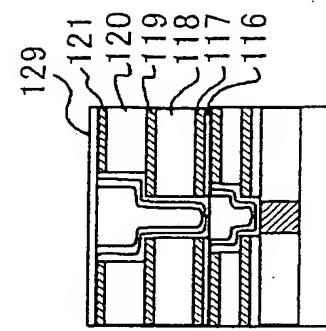
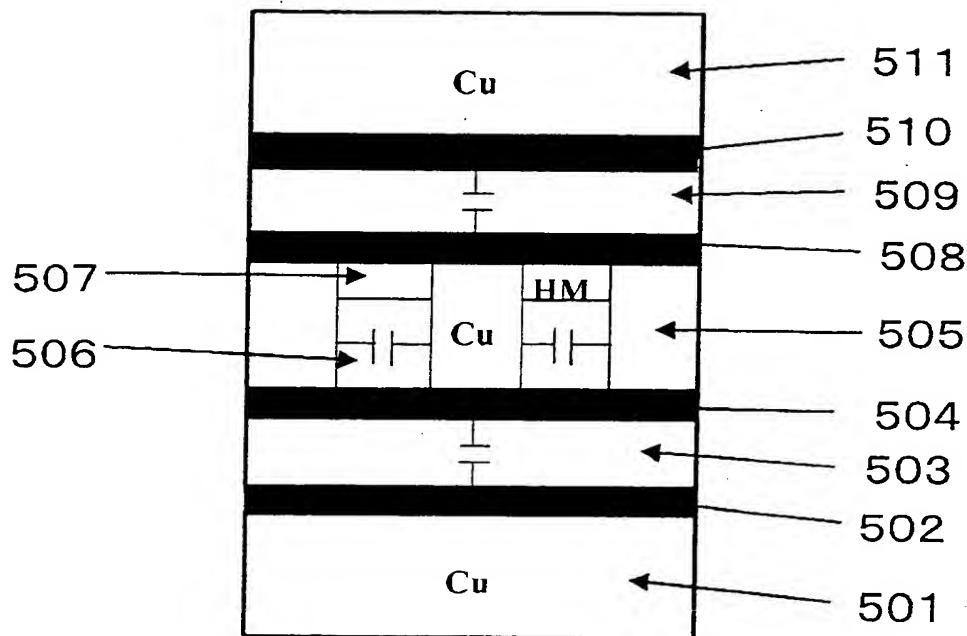


FIG. 14



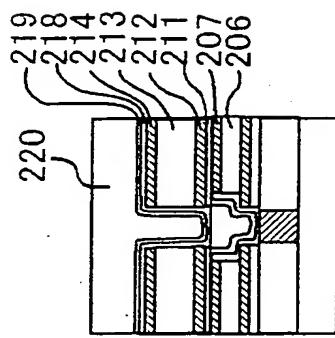


FIG. 15d

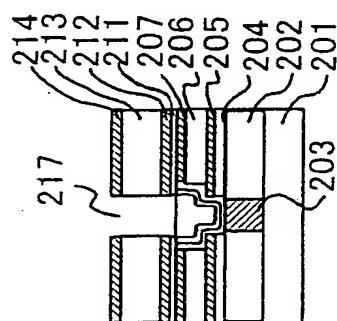


FIG. 15c

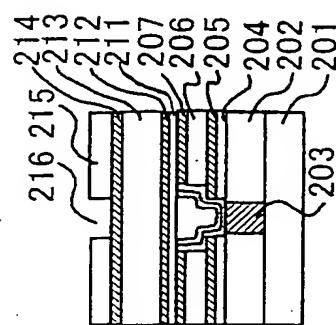


FIG. 15b

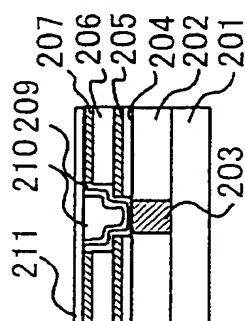


FIG. 15a

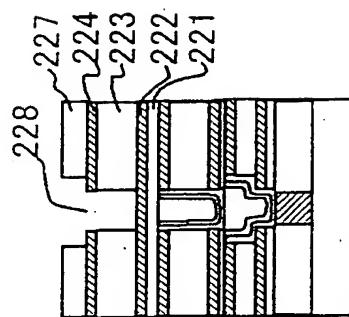


FIG. 15h

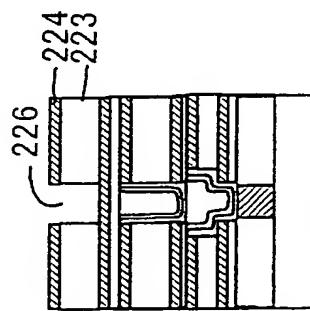


FIG. 15g

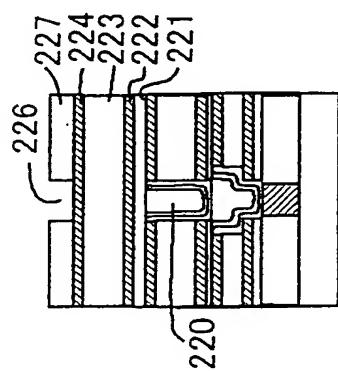


FIG. 15f

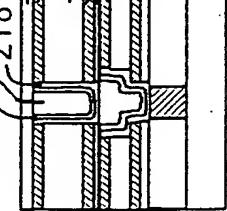


FIG. 15e

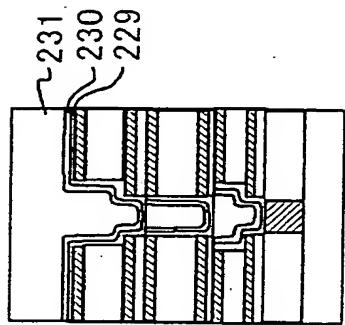


FIG. 15j

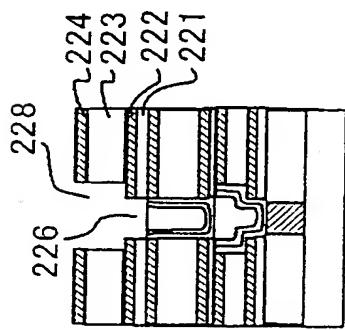


FIG. 15i

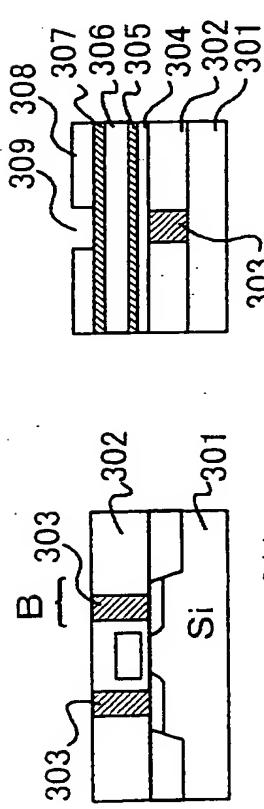


FIG. 16a

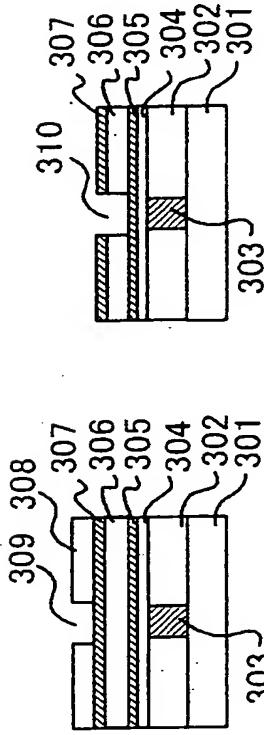


FIG. 16b

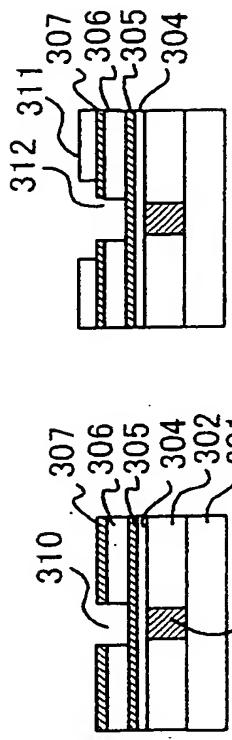


FIG. 16c

FIG. 16d

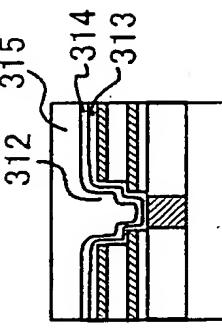
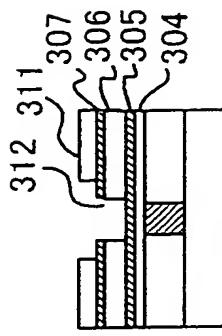


FIG. 16e

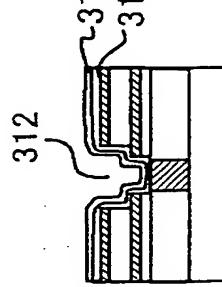


FIG. 16f

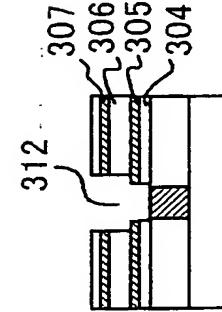


FIG. 16g

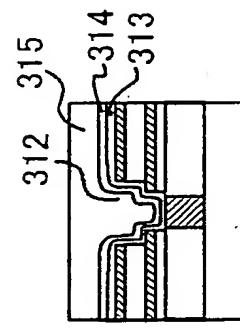


FIG. 16h

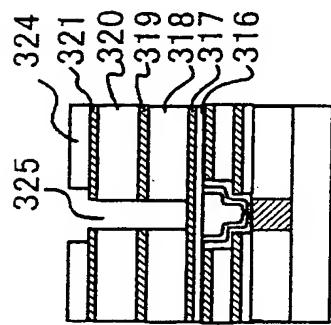


FIG. 16l

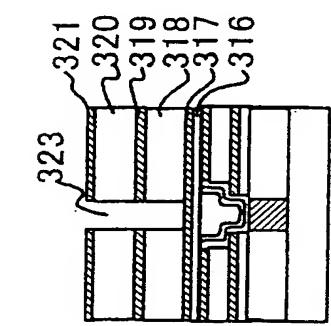


FIG. 16k

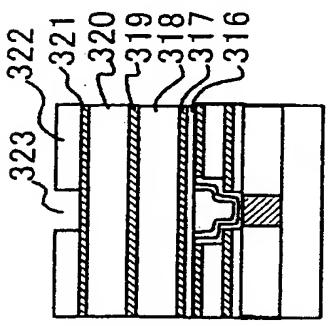


FIG. 16j

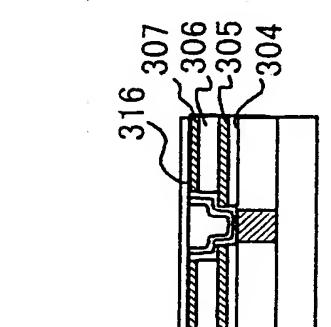


FIG. 16i

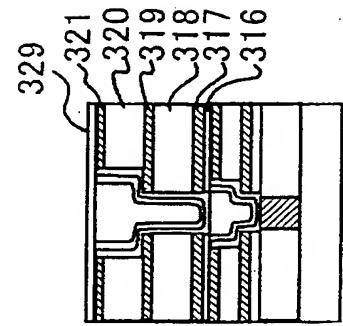


FIG. 16l

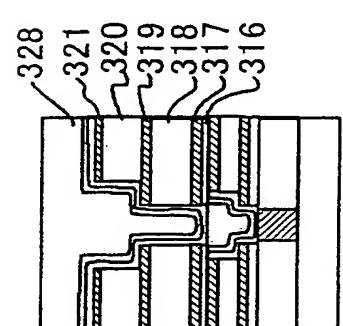


FIG. 16k

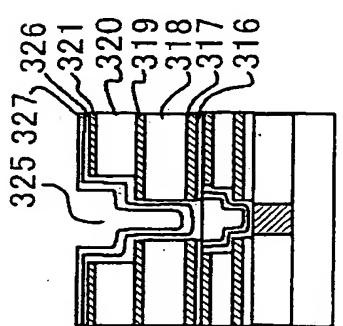


FIG. 16j

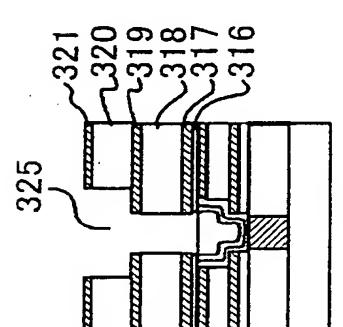


FIG. 16i

FIG. 16l

FIG. 16k

FIG. 16j

FIG. 16i

FIG. 16l

FIG. 16k

FIG. 16j

FIG. 16i

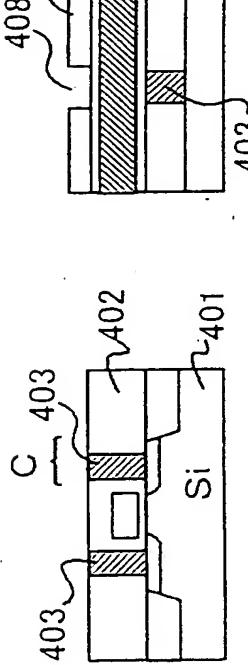


FIG. 17a

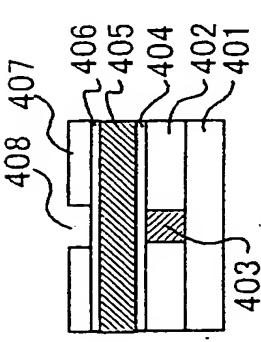


FIG. 17b

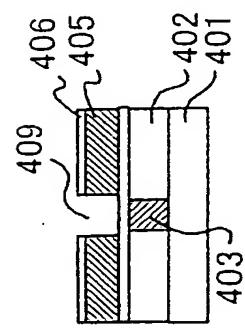


FIG. 17c

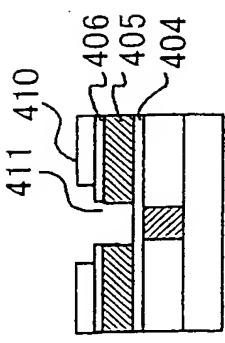


FIG. 17d

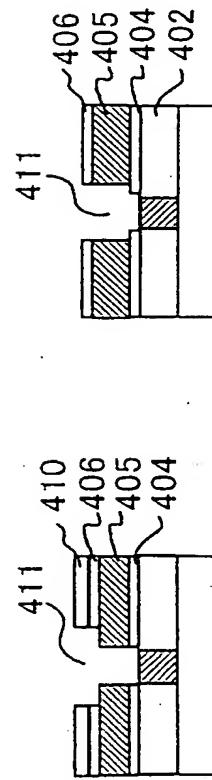


FIG. 17e

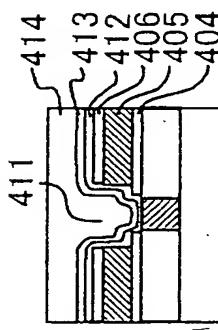


FIG. 17f

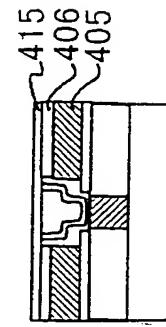


FIG. 17g

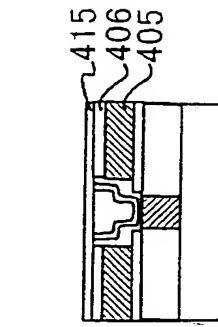


FIG. 17h

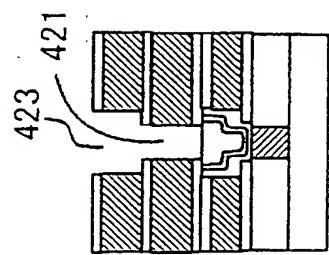


FIG. 17i

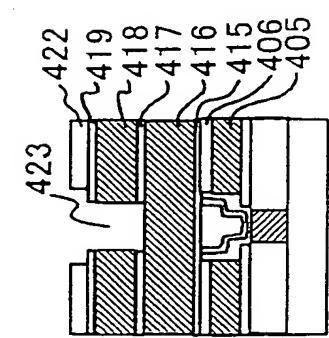


FIG. 17j

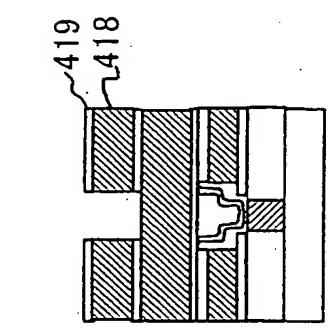


FIG. 17k

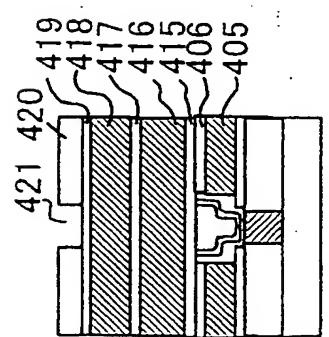


FIG. 17l

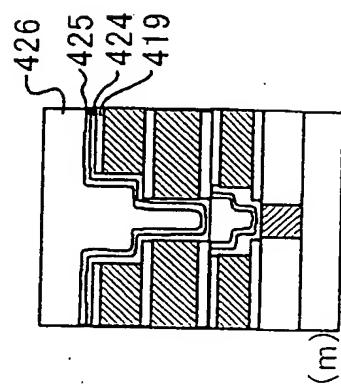


FIG. 17m

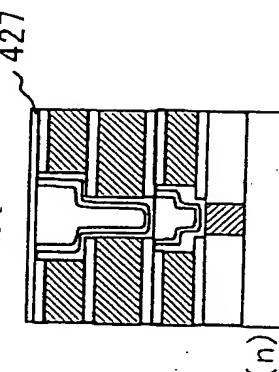
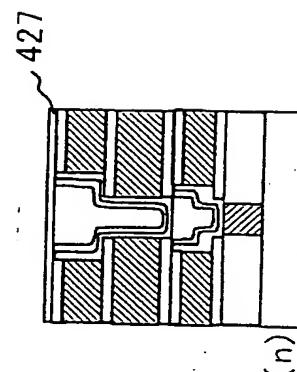


FIG. 17n

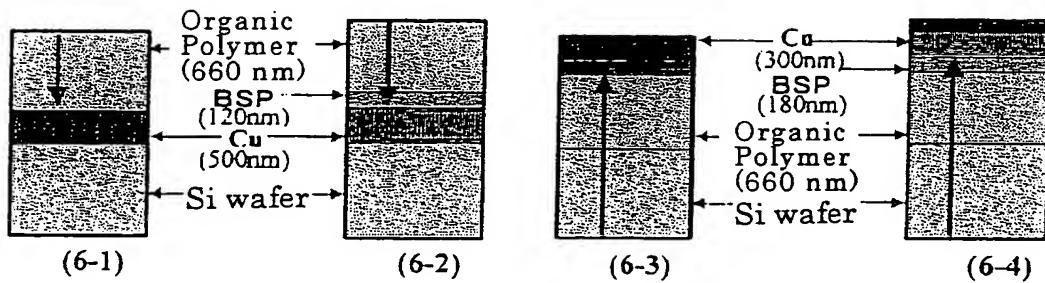


(n)

FIG. 17o

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FIG. 18a



	Structure	Cu atoms/cm ³
1	Si / Cu(500nm) / OP(660nm)	5×10^{18}
2	Si / Cu(500nm) / BSP(120nm) / OP(660nm)	8×10^{17}
3	Si / OP(660nm) / Cu(300nm)	6×10^{17}
4	Si / OP(660nm) / BSP(180nm) / Cu(300nm)	1×10^{17}

FIG. 18b

FIG. 19

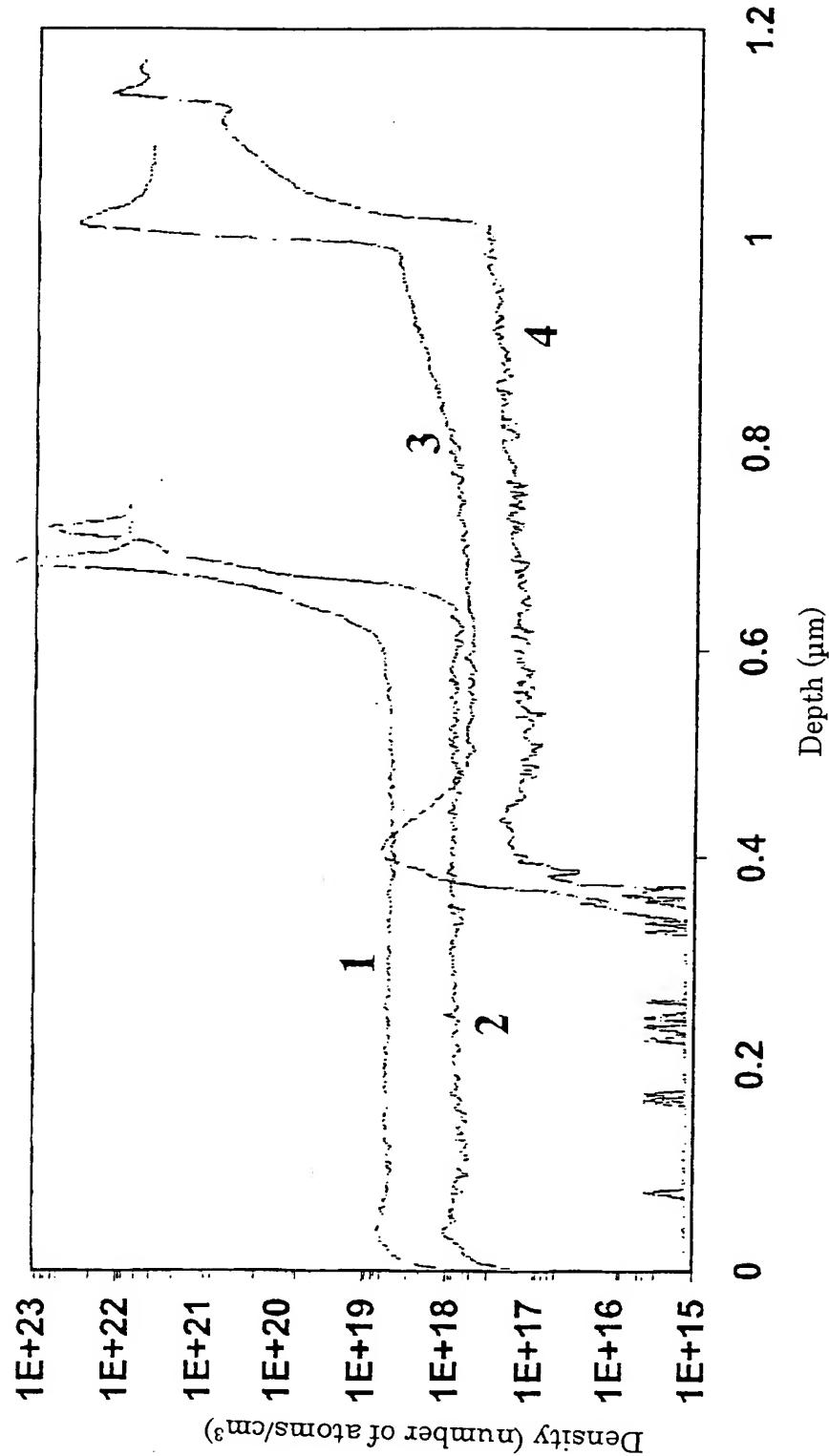
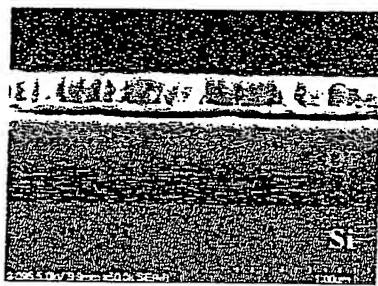


FIG. 20a



Annealing
400°C
6 hrs

FIG. 20b



Annealing
400°C
6 hrs

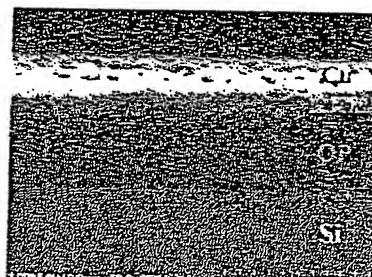


FIG. 20c

FIG. 20d

FIG. 21a

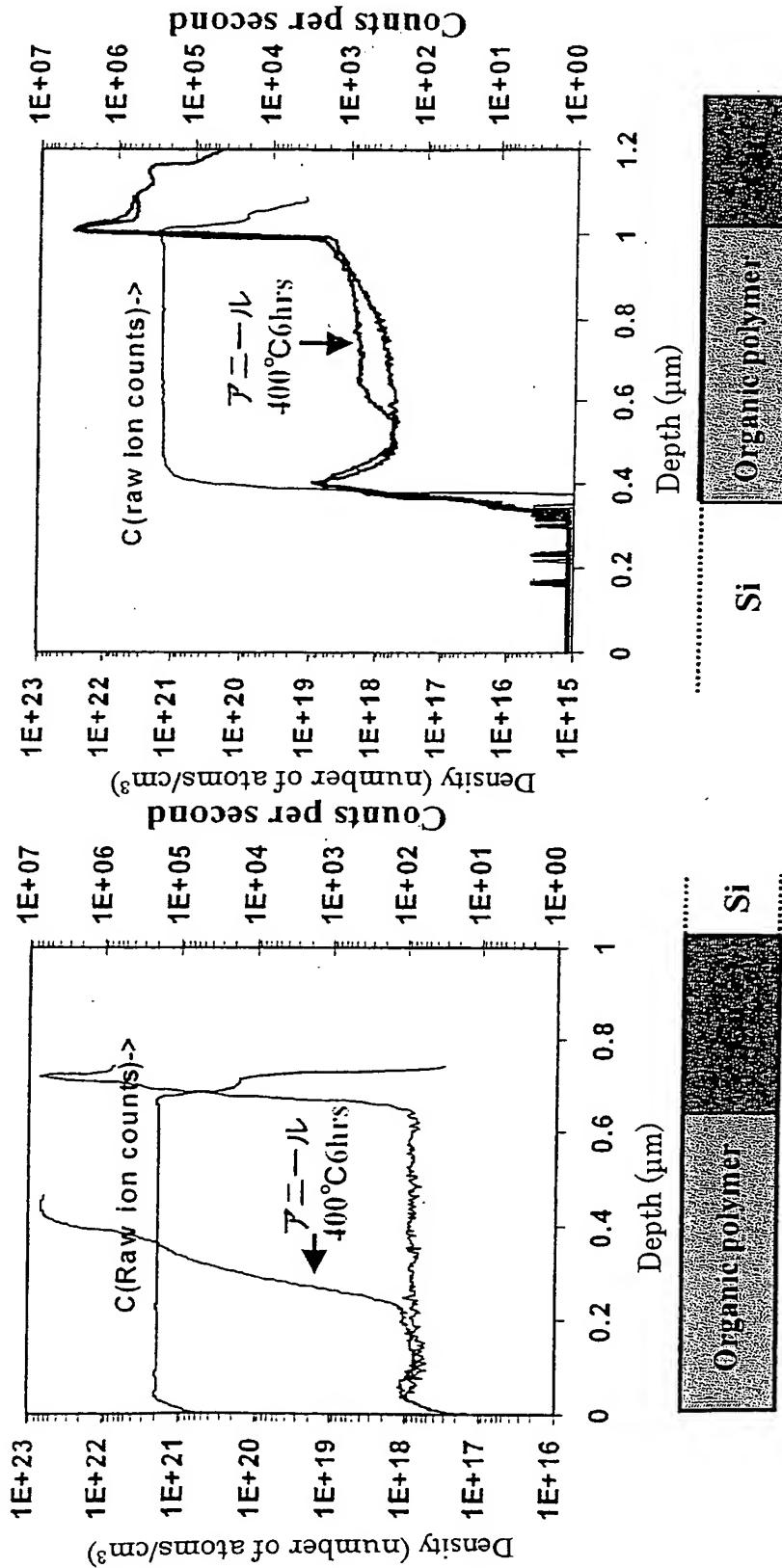


FIG. 21b

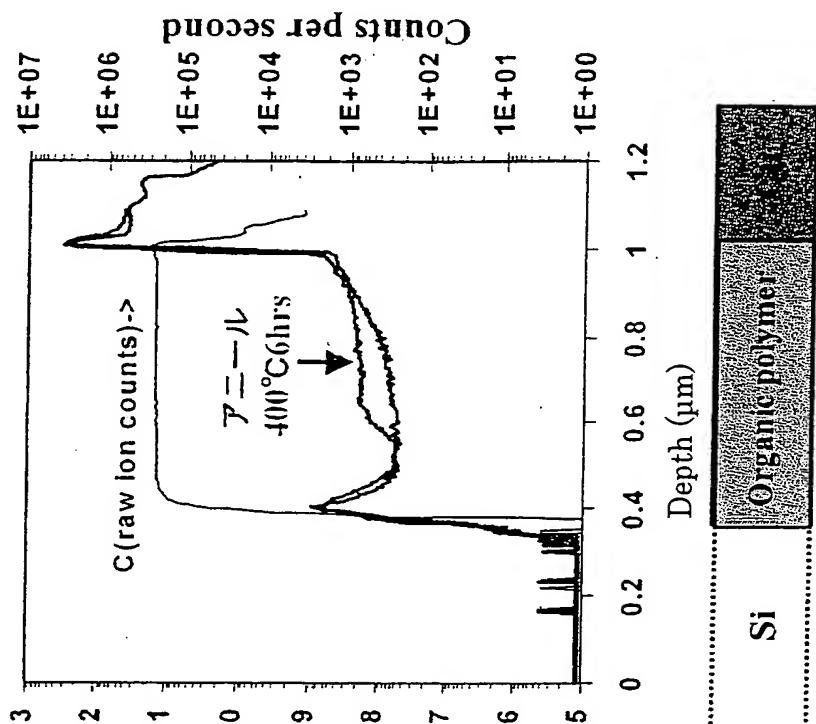
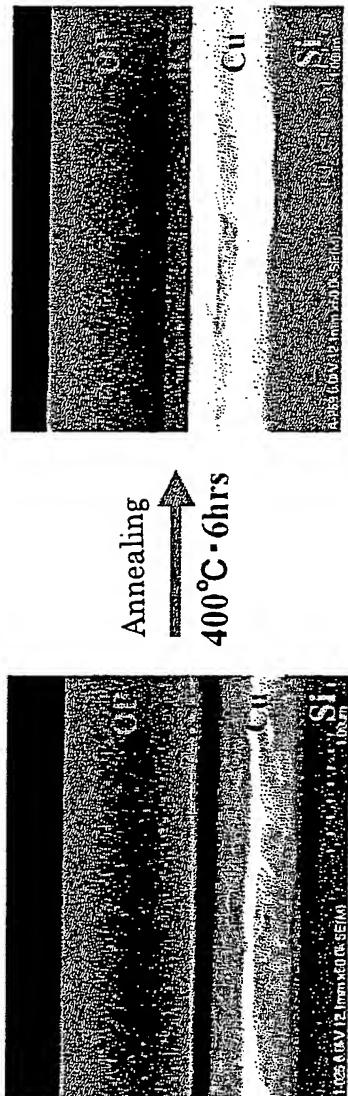


FIG. 21c

FIG. 21d

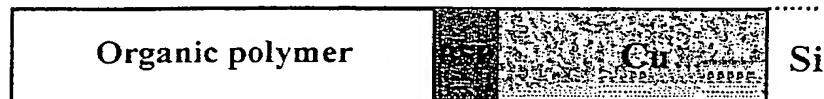
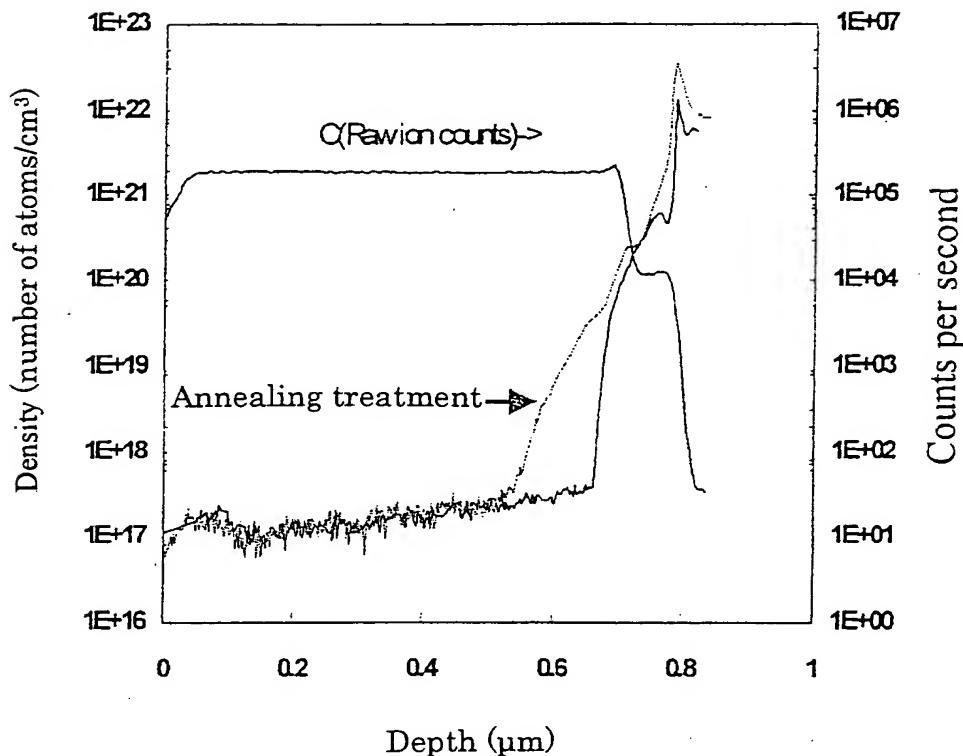
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F I G. 22



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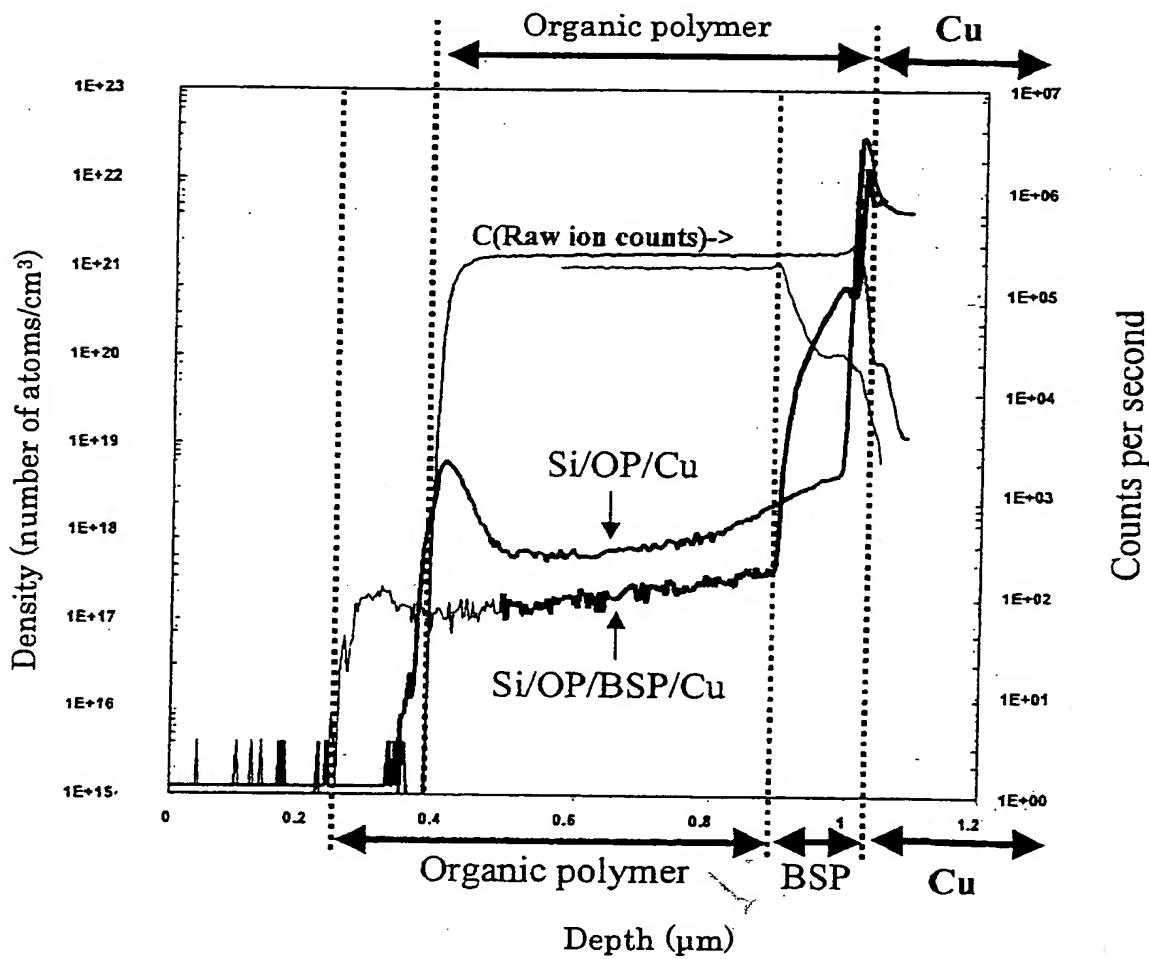
F I G. 23a



F I G. 23b

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FIG. 24



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